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Indian Standard

SPECIFICATION FOR QUARTZ CRYSTAL UNITS USED FOR FREQUENCY CONTROL AND SELECTION

PART 5 SERIES CX FOR OSCILLATORS

Section 2 Quartz Crystal Unit Type CX-02

- **0.** General This standard shall be read in conjunction with IS: 8271 (Part 1)-1981 'Specification for quartz crystal units used for frequency control and selection: Part 1 General requirements and tests (*first revision*)'.
- 1. Outline and Dimensions Holder outline shall conform to type CX [see IS : 4570 (Part 6)-1984 Specification for crystal unit holders: Part 6 Metal, solder seal, two pin crystal unit holder types CX].
- 2. Marking See 8 of IS: 8271 (Part 1)-1981.
- 3. Construction and Workmanship See 7 of IS: 8271 (Part 1)-1981.
- 4. Test Schedule and Detail Requirements
- 4.1 General Conditions for Test See 9.2 of IS: 8271 (Part 1)-1981.
- **4.2** Test Schedule The sequence and grouping of type, routine and acceptance tests shall be as per **9.1** of IS: 8271 (Part 1)-1981.
- **4.3** Detail Requirements The detail requirements applicable to this particular type of crystal unit shall be as specified in Table 1.

l No.	Characteristics	Requirements	
i)	Type of holder	CX (see 1)	
ii)	Frequency range	2.9 to 20 MHz	
iii)	Frequency tolerance:		
	a) Operating temperature range	\pm 50 ppm	
iv)	Load capacitance	30·0 ± 0·5 pF	
v)	Mode of oscillation	Fundamental	
vi)	Operating temperature range	- 55°C to + 105°C	
vii)	Test set, calibration values and rated drive level	See Table 2	
viii)	Capacitance shunt	7 pF maximum	
ix)	Resonance resistance	See Table 3	
x)	Shock [as per 9.15 (Severity A) of IS: 8271 (Part 1)-1981]:		
	a) Frequency change permitted	\pm 5 ppm	
	b) Resonance resistance change permitted	± 10 percent	
xi)	Vibration [as per 9.16.1 (Severity A) of IS: 8271 (Part 1)-1981]:		
	a) Frequency change permitted	± 5 percent	
	b) Resonance resistance change permitted	± 10 percent	
xii)	Temperature cycling:	1. E. nom	
 a) Frequency change permitted b) Resonance resistance change permitted 		\pm 5 ppm \pm 10 percent	
xiii)	Ageing: i) Frequency change permitted	5 ppm	
	1) Frequency shangs parimeter		

TABLE 2 TEST SET, CALIBRATION VALUES AND RATED DRIVE LEVEL

[Table 1 (vii)]

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SI Frequency	Frequency Range	Calibration Values			Rated Drive	Test Set
NO.		Resistance Crystal Resistor Vol- Current tage Drop	revei			
(1)	(2) MHz	(3) ohms	(4) mA	(5) Volts	(6) mW	(7)
i)	From 2.9 to 5.1	50	10		5·0 ± 1·0	
ii)	Over 5.1 to 7.5	22	15		5·0 ± 1·0	TS-330/TSM
iii)	Over 7.5 to 10	13	20		5.0 ± 1.0	
iv)	Over 10 to 20	10		0.22	5·0 ± 1·0	TS-683/TSM

TABLE 3 EQUIVALENT RESONANCE RESISTANCE

SI No.	Frequency Range	Maximum Resonance Resistance
(1)	(2)	(3)
	MHz	σhm s
i)	From 2.9 to 3.75	180
ii)	Over 3:75 to 4:75	120
iii)	Over 4.75 to 6	75
iv)	Over 6 to 7	50
v)	Over 7 to 10	30
vi)	Over 10 to 20	25

EXPLANATORY NOTE

This standard (Part 5/Sec 2) covers the requirements of crystal units quartz, style QC-21 of JSS 50906 (1971) 'Detail specification for crystal unit, quartz styles QC-20, QC-21, QC-22, QC-23 and QC-26' issued by the Directorate of Standardization, Ministry of Defence (India).